



# M I C A : Microscopic ChAracterization of functional and nanostructured materials

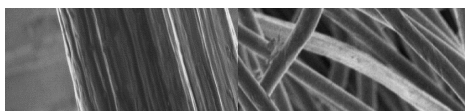
## WHAT WE OFFER : services and expertise

- Characterization / test / analysis performed by highly qualified UCLouvain members
- Microscopy characterization tools in the context of materials science, chemistry, solid-state physics, and (bio)nanotechnology



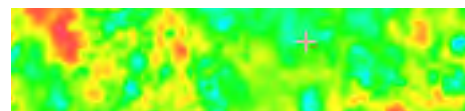
### Scanning Probe Microscopy (SPM)

- Surface topography in air or liquid
- Mechanical property analysis
- Electric property analysis
- Magnetic property analysis



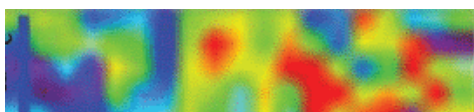
### Scanning Electron Microscopy (SEM)

- Micro- and nano- morphology
- STEM analysis
- Chemical mapping



### Infrared Spectrometer

- Infrared absorption spectrum
- Molecules structure
- Chemical mapping



### Raman Spectrometer

- Vibrational modes of molecules
- Chemical mapping



### Sample preparation tools

- Cryo-ultramicrotomy
- Sputters (carbon and metal)

## CONTACT

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[www.uclouvain.be/mica](http://www.uclouvain.be/mica)

(1) AFM BRUKER Multimode – (2) AFM Bruker ICON – (3) FEG-SEM JEOL 7600F – (4) IR THERMOFISHER Nicolet IN10 – (5) RAMAN THERMOFISHER DXR